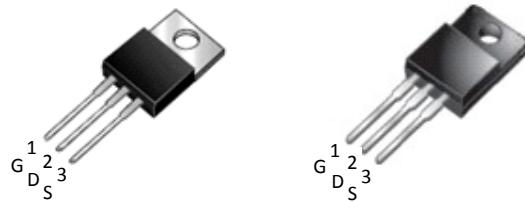


650V / 8A N-Channel Enhancement Mode MOSFET	650V, $R_{DS(ON)} = 1.4\Omega$ @ $V_{GS} = 10V$, $I_D = 4.0A$
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Features

- Low ON Resistance
- Fast Switching
- Low Gate Charge & Low C_{RSS}
- Fully Characterized Avalanche Voltage and Current
- Specially Designed for AC Adapter, Battery Charger and SMPS
- In compliance with EU RoHS 2002/95/EC Directives



TO-220AB

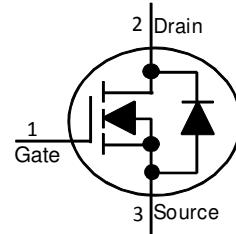
ITO-220AB

Mechanical Information

- Case: TO-220AB / ITO-220AB Molded Plastic
- Terminals : Solderable per MIL-STD-750, Method 2026

Marking & Ordering Information

TYPE	MARKING	PACKAGE	PACKING
HY8N65T	8N65T	TO-220AB	50PCS/TUBE
HY8N65FT	8N65FT	ITO-220AB	50PCS/TUBE

**Absolute Maximum Ratings ($T_c = 25^\circ C$ unless otherwise noted)**

Parameter	Symbol	HY8N65T	HY8N65FT	Units
Drain-Source Voltage	V_{DS}	650		V
Gate-Source Voltage	V_{GS}	± 30		V
Continuous Drain Current	I_D	8	8	A
Pulsed Drain Current ¹⁾	I_{DM}	32	32	A
Maximum Power Dissipation Derating Factor	P_D	125 1.0	45 0.36	W
Avalanche Energy with Single Pulse $I_{AS} = 8A$, $VDD = 50V$, $L = 13mH$	E_{AS}	416		mJ
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55 to +150		°C

Note : 1. Maximum DC current limited by the package

Thermal Characteristics

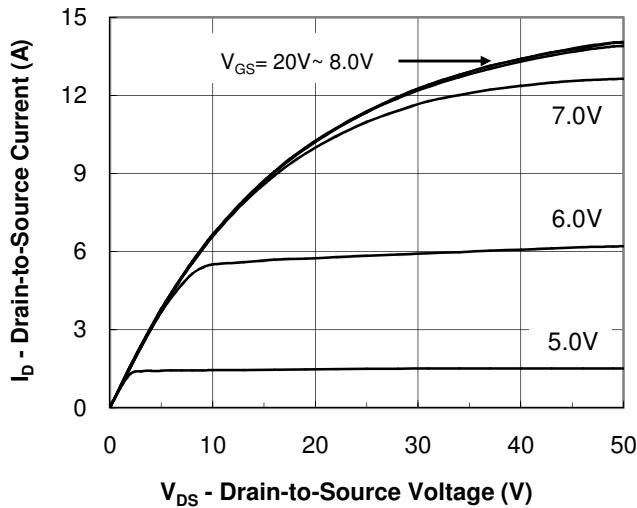
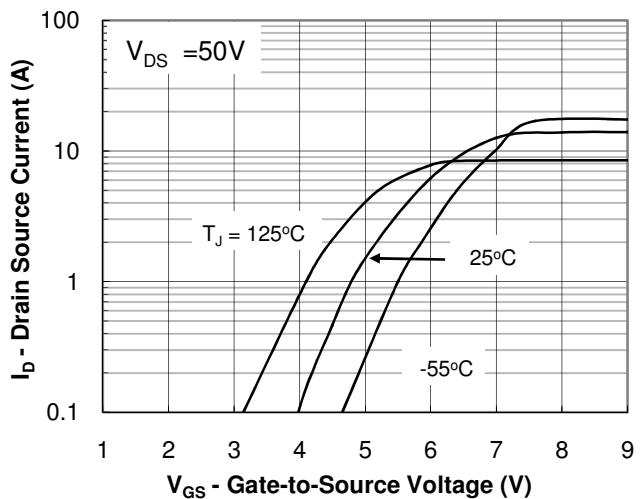
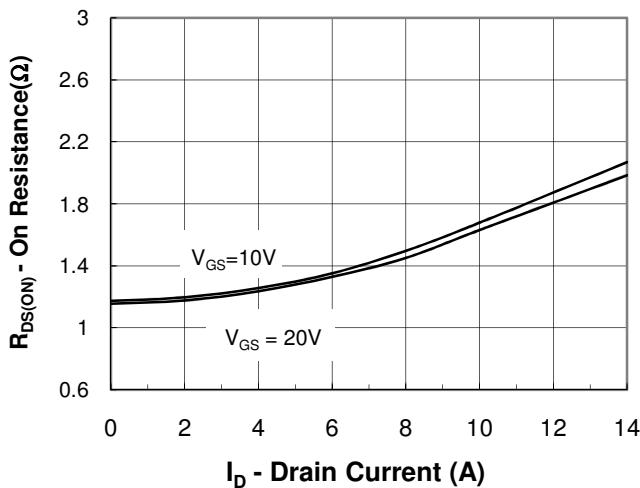
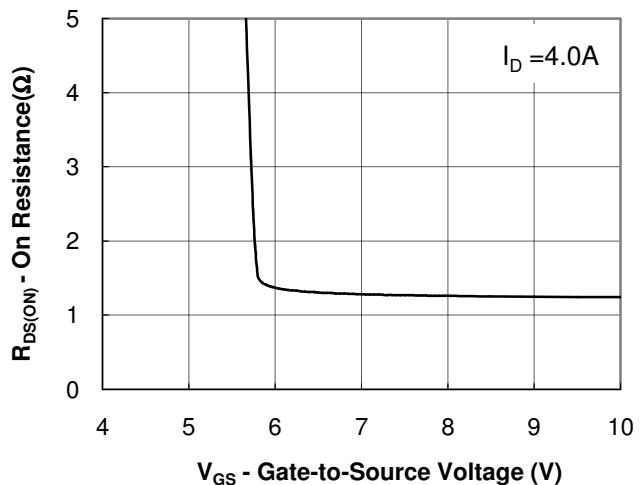
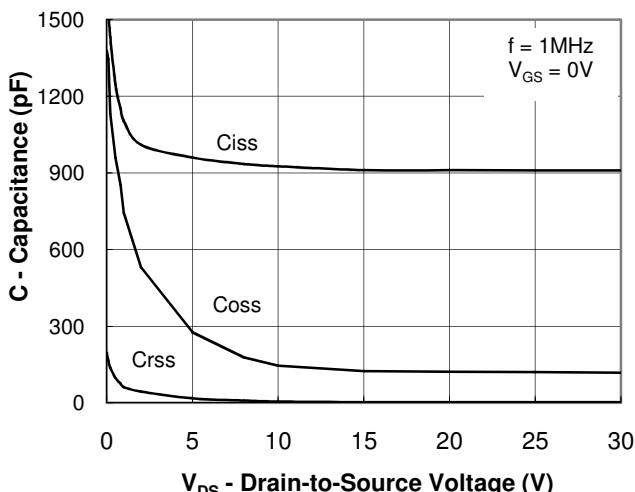
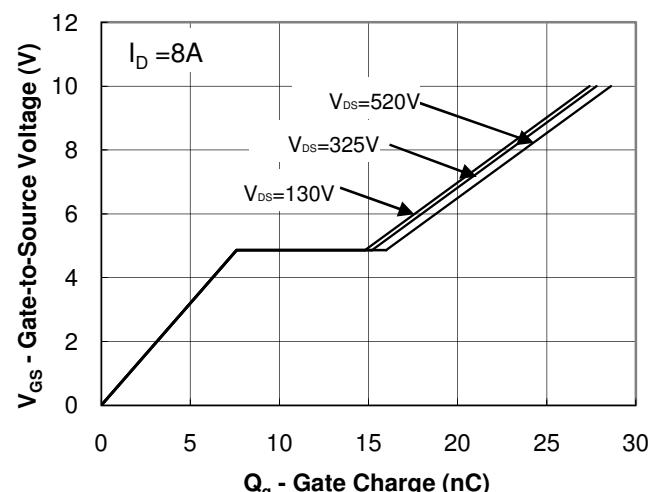
PARAMETER	Symbol	HY8N65T	HY8N65FT	Units
Junction-to-Case Thermal Resistance	$R_{\theta JC}$	1.0	2.78	°C/W
Junction-to Ambient Thermal Resistance	$R_{\theta JA}$	62.5	100	°C/W

COMPANY RESERVES THE RIGHT TO IMPROVE PRODUCT DESIGN, FUNCTIONS AND RELIABILITY WITHOUT NOTICE

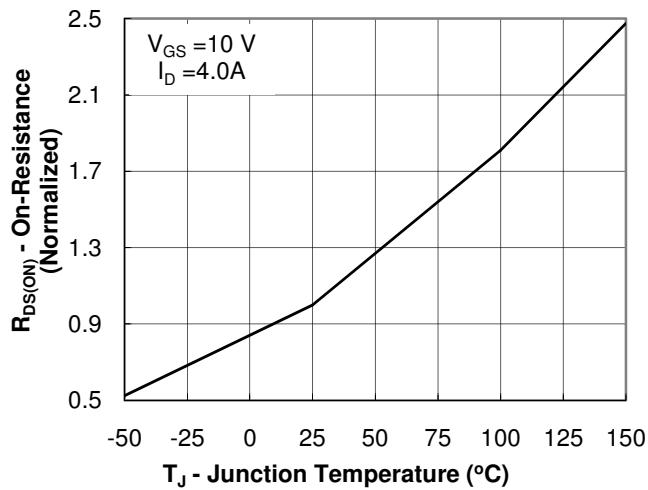
Electrical Characteristics ($T_c=25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Test Condition	Min.	Typ.	Max.	Units
Static						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	650	-	-	V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	2.0	-	4.0	V
Drain-Source On-State Resistance	$R_{\text{DS(on)}}$	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=4.0\text{A}$	-	1.2	1.4	Ω
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}}=650\text{V}, V_{\text{GS}}=0\text{V}$	-	-	10	μA
Gate Body Leakage	I_{GSS}	$V_{\text{GS}}=\pm 30\text{V}, V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
Dynamic						
Total Gate Charge	Q_g	$V_{\text{DS}}=520\text{V}, I_{\text{D}}=8\text{A}, V_{\text{GS}}=10\text{V}$	-	28.6	38	nC
Gate-Source Charge	Q_{gs}		-	7.6	-	
Gate-Drain Charge	Q_{gd}		-	8.4	-	
Turn-On Delay Time	$t_{\text{d(on)}}$	$V_{\text{DD}}=325\text{V}, I_{\text{D}}=8\text{A}$ $V_{\text{GS}}=10\text{V}, R_{\text{G}}=25\Omega$	-	13.2	18	ns
Turn-On Rise Time	t_r		-	18.6	32	
Turn-Off Delay Time	$t_{\text{d(off)}}$		-	42.6	56	
Turn-Off Fall Time	t_f		-	16.8	22	
Input Capacitance	C_{iss}	$V_{\text{DS}}=25\text{V}, V_{\text{GS}}=0\text{V}$ $f=1.0\text{MHz}_z$	-	900	1120	pF
Output Capacitance	C_{oss}		-	120	180	
Reverse Transfer Capacitance	C_{rss}		-	2.2	6.8	
Source-Drain Diode						
Max. Diode Forward Current	I_s	-	-	-	8	A
Max. Pulsed Source Current	I_{SM}	-	-	-	32	A
Diode Forward Voltage	V_{SD}	$I_s=8\text{A}, V_{\text{GS}}=0\text{V}$	-	-	1.3	V
Reverse Recovery Time	t_{rr}	$V_{\text{GS}}=0\text{V}, I_{\text{F}}=8\text{A}$ $di/dt=100\text{A}/\mu\text{s}$	-	380	-	ns
Reverse Recovery Charge	Q_{rr}		-	3.6	-	μC

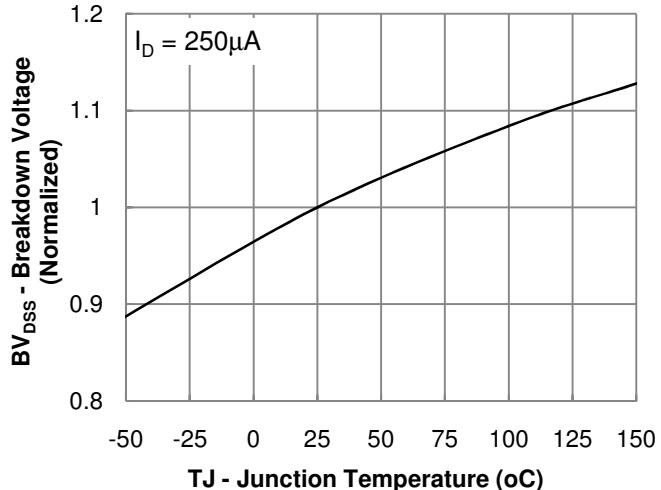
NOTE : Plus Test : Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$.

Typical Characteristics Curves ($T_C=25^\circ\text{C}$, unless otherwise noted)
**Fig.1 Output Characteristic****Fig.2 Transfer Characteristic****Fig.3 On-Resistance vs Drain Current****Fig.4 On-Resistance vs Gate to Source Voltage****Fig.5 Capacitance Characteristic****Fig.6 Gate Charge Characteristic**

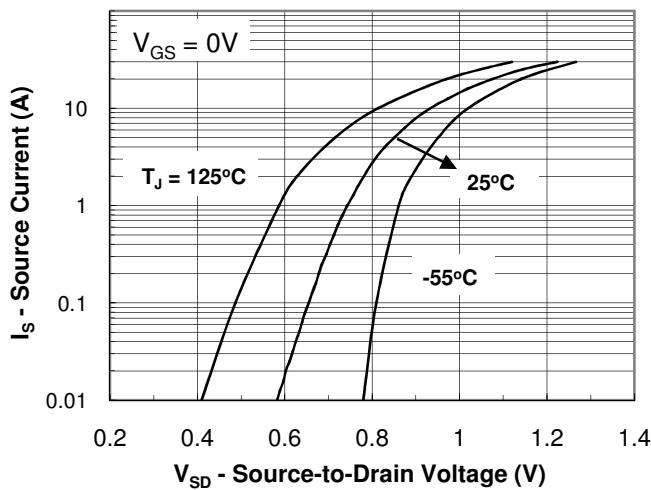
Typical Characteristics Curves ($T_C=25^\circ\text{C}$, unless otherwise noted)



**Fig.7 On-Resistance
vs Junction Temperature**



**Fig.8 Breakdown Voltage
vs Junction Temperature**



**Fig.9 Body Diode
Forward Voltage Characteristic**